
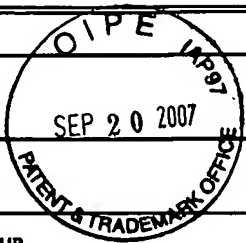



Sheet 1 of 1				ATTY DOCKET NO. 2002_0034A		SERIAL NO. 10/046,512			
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Hiroshi HAMASAKA et al.					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				FILING DATE January 16, 2002			GROUP 2615		
Date Submitted to PTO: June 20, 2003									
U.S. PATENT DOCUMENTS									
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
	AA	6,181,870	1/2001	Okada et al.					
	AB								
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FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO		
	AJ	2000-324444 ✓	11/2000	JP			Abstract		
	AK	2000-261741 ✓	9/2000	JP			Abstract		
	AL	9-312827 ✓	12/1997	JP			Abstract		
	AM	2000-152183 ✓	5/2000	JP			Abstract		
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EXAMINER					DATE CONSIDERED				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1				FORM PTO 1449 (modified)		ATTY DOCKET NO. 2002_0034A		SERIAL NO. 10/046,512	
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	AA	6,181,870	1/2001	Okada et al.			<div style="font-size: 2em; font-weight: bold; margin-bottom: 10px;">COPY</div> <div style="font-weight: bold; margin-bottom: 10px;">RECEIVED</div> <div style="font-weight: bold;">JUN 23 2003</div> <div style="font-weight: bold;">Technology Center 2600</div>		
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO		
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DT	AK	2000-261741 ✓	9/2000	JP			Abstract		
DT	AL	9-312827 ✓	12/1997	JP			Abstract		
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	AO								
	AP								
	AQ								
EXAMINER /Daniel Tekle/				DATE CONSIDERED 07/17/2006					

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